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**PCN# : P63EAAB**  
**Issue Date : May. 04, 2016**

**DESIGN/PROCESS CHANGE NOTIFICATION**

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

**Implementation of change:**

Expected First Shipment Date for Changed Product :Aug. 02, 2016

Expected First Date Code of Changed Product :1632

**Description of Change (From) :**

LSOP products are classified at Moisture Sensitivity Level 1 (MSL 1). No dry pack for LSOP with MSL 1.

**Description of Change (To) :**

Re-classification of Moisture Sensitivity Level for LSOP products to Level 3. Packing template to include dry pack for LSOP MSL 3.

**Reason for Change:**

Moisture Sensitivity Level (MSL) rating re-classification according to product's capability and assembly from Philippines subcontractor.

**Affected Product(s):**

FSL206MRL	FSQ0165RLX	FSQ0265RLX
FSQ0365RLX	FSQ0370RLA	FSQ321L
FSQ321LX		

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSQ0370RLA	ATEC - 8LSOP	SDG4 / Q-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 560V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	125C, 22V/50V/560V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 22V/100V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSL136HRL	ATEC - 8LSOP	FS50D2D / UNI-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 520V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	125C, 26V/50V/520V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 26V/100V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSQ510M	ATEC - 7LSOP	SDG4D	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 560V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	100C, 5V/20V/50V/400V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 11V/5V/50V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77



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**Title : Qualification Report for PCN : P63EAAB**

**Date : May. 04, 2016**

**Affected devices :**

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<b>Product</b>	<b>Customer Part Number</b>	<b>BBB</b>	<b>Drawing</b>
FSQ321LX		Y	N

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<b>Product</b>	<b>Customer Part Number</b>	<b>BBB</b>	<b>Drawing</b>
FSL206MRL		Y	N
FSQ0165RLX		Y	N
FSQ0265RLX		Y	N
FSQ0370RLA		Y	N

**Qualification Test Summary :**

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSQ0370RLA	ATEC - 8LSOP	SDG4 / Q-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 560V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	125C, 22V/50V/560V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 22V/100V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSL136HRL	ATEC - 8LSOP	FS50D2D / UNI-FET	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 520V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	125C, 26V/50V/520V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 26V/100V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20140067	FSQ510M	ATEC - 7LSOP	SDG4D	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL3 Precondition	260°C, 3 cycles	JESD22-A113	-	0/231
High Temperature Reverse Bias	125C, 560V	JESD22-A108	1000 hrs	0/77
High Temperature Operating Life test	100C, 5V/20V/50V/400V	JESD22-A108	1000 hrs	0/77
High Accelerate Stressed Test	130C, 85%RH, 11V/5V/50V	JESD22-A101	96 hrs	0/77
High Temperature Storage Test	150C	JESD22-A103	1000 hrs	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500cyc	0/77

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

Please contact your local Customer Quality Engineer if you have any questions concerning this data.